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TOSHIBA Photocoupler GaAlAs Ired & Photo-IC

TLP250

Transistor Inverter Inverter For Air Conditionor **IGBT Gate Drive** Power MOS FET Gate Drive

The TOSHIBA TLP250 consists of a GaAlAs light emitting diode and a integrated photodetector. This unit is 8-lead DIP package. TLP250 is suitable for gate driving circuit of IGBT or power MOS FET.

- Input threshold current: IF=5mA(max.) ٠
- Supply current (I_{CC}): 11mA(max.)
- Supply voltage (VCC): 10-35V •
- Output current (I_O): ±1.5A (max.)
- Switching time (tpLH/tpHL): 1.5µs(max.)
- Isolation voltage: 2500Vrms(min.)
- UL recognized: UL1577, file No.E67349
- Option(D4)

VDE Approved : DIN EN60747-5-2 Maximum Operating Insulation Voltage : 890VPK Highest Permissible Over Voltage : 4000Vpk

(Note):When a EN60747-5-2 approved type is needed, Please designate "Option(D4)"



Weight: 0.54 g(Typ.)

Pin Configuration (top view)





Truth Table

		Tr1	Tr2
Input LED	On	On	Off
	Off	Off	On

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Maximum Ratings (Ta = 25°C)

	Characteristic	Symbol	Rating	Unit	
	Forward current			20	mA
	Forward current derating (Ta ≥ 70°C)		ΔI _F / ΔTa	-0.36	mA / °C
LED	Peak transient forward curent	(Note 1)	IFPT	1	А
	Reverse voltage			5	V
	Junction temperature	Tj	125	°C	
	"H"peak output current ($P_W \le 2.5\mu$ s,f ≤ 15 kHz)	(Note 2)	I _{OPH}	-1.5	А
	"L"peak output current (P _W ≤ 2.5µs,f ≤ 15kHz)	(Note 2)	I _{OPL}	+1.5	А
or	Output usktore	(Ta ≤ 70°C)	N/-	35	V
	Output voltage	(Ta = 85°C)	Vo	24	v
Detector	Supply veltage	(Ta ≤ 70°C)	Maa	35	V
Ğ	Supply voltage	(Ta = 85°C)	Vcc	24	V
	Output voltage derating (Ta ≥ 70°C)	ΔV _O / ΔTa	-0.73	V / °C	
	Supply voltage derating (Ta ≥ 70°C)	ΔV_{CC} / ΔTa	-0.73	V / °C	
	Junction temperature		Tj	125	°C
Oper	ating frequency	f	25	kHz	
Oper	Operating temperature range			-20~85	°C
Stora	Storage temperature range			-55~125	°C
Lead	Lead soldering temperature (10 s)			260	°C
Isolat	Isolation voltage (AC, 1 min., R.H.≤ 60%) (Note 4)			2500	Vrms

(Note 1) Pulse width $P_W \le 1\mu s$, 300pps

(Note 2) Exporenential wavefom

(Note 3) Exporenential waveform, $I_{OPH} \le -1.0A(\le 2.5\mu s)$, $I_{OPL} \le +1.0A(\le 2.5\mu s)$

- (Note 4) Device considerd a two terminal device: Pins 1, 2, 3 and 4 shorted together, and pins 5, 6, 7 and 8 shorted together.
- (Note 5) A ceramic capacitor(0.1μF) should be connected from pin 8 to pin 5 to stabilize the operation of the high gain linear amplifier. Failure to provide the bypassing may impair the switching proparty. The total lead length between capacitor and coupler should not exceed 1cm.

Characteristic Symbol Min Тур. Max Unit Input current, on (Note6) 7 10 mΑ I_{F(ON)} 8 0 0.8 V Input voltage, off V_{F(OFF)} ____ 15 30 V Supply voltage V_{CC} 20 ____ _ Peak output current IOPH/IOPL ±0.5 А ____ °C Operating temperature -20 25 70 85 Topr

Recommended Operating Conditions

Note 6:Input signal rise time(fall time)<0.5µs.

Electrical Characteristics (Ta = $-20 \sim 70^{\circ}$ C, unless otherwise specified)

Characteristic		Symbol	Test Cir– cuit	Test Condition		Min	Тур.*	Max	Unit
Input forward voltage		VF	_	I _F = 10 mA , Ta = 25°C		_	1.6	1.8	V
Temperature coefficient of forward voltage		ΔV _F /ΔTa	_	I _F = 10 mA		_	-2.0	_	mV / °C
Input reverse current		IR	_	V _R = 5V, Ta = 25°C		_	_	10	μA
Input capacitance		CT	_	V = 0 , f = 1MHz , Ta = 25°C		_	45	250	pF
Output current	"H" level	I _{OPH}	1		F = 10 mA / ₈₋₆ = 4V	-0.5	-1.5	_	A
	"L" level	I _{OPL}	2		F = 0 V ₆₋₅ = 2.5V	0.5	2	_	
Output voltage	"H" level	V _{OH}	3	$V_{CC1} = +15V, V_{EE1} = -15V$ R _L = 200Ω, I _F = 5mA		11	12.8	_	v
	"L" level	V _{OL}	4	$V_{CC1} = +15V, V_{EE1} = -15V$ R _L = 200Ω, V _F = 0.8V		_	-14.2	-12.5	
	"H" level	Іссн	_	V _{CC} = 30V, I _F = 10mA Ta = 25°C		_	7	_	- mA
Supply current				V _{CC} = 30V, I _F = 10mA		_	_	11	
Supply current	"L" level	ICCL	_	V _{CC} = 30V, I _F = 0mA Ta = 25°C		_	7.5	_	
				$V_{CC} = 30V, I_F = 0mA$		-		11	
Threshold input current	"Output L→H"	I _{FLH}	_	$V_{CC1} = +15V, V_{EE1} = -15V$ $R_L = 200\Omega, V_O > 0V$		—	1.2	5	mA
Threshold input voltage	"Output H→L"	V_{FHL}	_	$V_{CC1} = +15V, V_{EE1} = -15V$ $R_L = 200\Omega, V_O < 0V$		0.8	_	_	V
Supply voltage		V _{CC}	_			10	_	35	V
Capacitance (input–output)		CS	—	$V_S = 0$, f = 1MHz Ta = 25		—	1.0	2.0	pF
Resistance(input-output)		R _S	_	V _S = 500V , Ta = 25°C R.H.≤ 60%		1×10 ¹²	10 ¹⁴	_	Ω

* All typical values are at Ta = 25°C (*1): Duration of I_O time \leq 50µs

Switching Characteristics (Ta = $-20 \sim 70^{\circ}$ C, unless otherwise specified)

Characteristic		Symbol	Test Cir– cuit	Test Condition	Min	Тур.*	Max	Unit
Propagation delay time	L→H	t _{pLH}	5	IF = 8mA V _{CC1} = +15V, V _{EE1} = −15V	—	0.15	0.5	
	H→L	tpHL			_	0.15	0.5	
Output rise time		tr	- 5	$R_L = 200\Omega$	—	_	-	μs
Output fall time		t _f			_	_	_	
Common mode transient immunity at high level C _{MH} output		V _{CM} = 600V, I _F = 8mA V _{CC} = 30V, Ta = 25°C	-5000	_	_	V/µs		
Common mode transier immunity at low level output	nt	C _{ML}	6	V _{CM} = 600V, I _F = 0mA V _{CC} = 30V, Ta = 25°C	5000	_	_	V/µs

All typical values are at $Ta = 25^{\circ}C$

Test Circuit 1 : IOPH



Test Circuit 2 : IOPL



Test Circuit 3 : VOH



Test Circuit 4 : VOL





Test Circuit 5: t_{pLH} , t_{pHL} , t_r t_f $0.1\mu F$ V_{O} V_{O} R_L V_{EE1}



Test Circuit 6: C_{MH}, C_{ML}



 $C_{ML}(C_{MH})$ is the maximum rate of rise (fall) of the common mode voltage that can be sustained with the output voltage in the low (high) state.

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Handbook" etc..

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